

U.S. Department of Commerce, Patent and Trademark Office				Atty Docket No.	Application No.			
				MST-1898-22D	10/800,382			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				Applicants				
				Leung et al.				
AUG 02 2004 PATENT & TRADEMARK OFFICE				Filing Date	Group			
				3/11/2004	Unknown			
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
JT	AA	3,585,378	15 May 1971	Bouricius et al.				
	AB	3,651,473	21 Mar 1972	Faber				
	AC	3,761,879	25 Sep 1973	Brandsma et al.				
	AD	3,803,562	9 Apr 1974	Hunter				
	AE	3,810,301	14 May 1974	Cook				
	AF	3,835,530	17 Sep 1974	Kilby				
	AG	3,849,872	26 Nov 1974	Hubacher				
	AH	3,859,640	7 Jan 1975	Eberlein et al.				
	AI	3,983,537	28 Sep 1976	Parsons et al.				
	AJ	4,007,452	8 Feb 1977	Hoff, Jr.				
JT	AK	4,038,648	26 Jul 1977	Chesley				
Foreign Patent Documents							Translation	
JT		Document	Date	Country	Class	Subclass	Yes	No
	AL	1002664	28 Dec 1976	Canada				
	AM	0162932 A3	4 Dec 1985	EP				
	AN	0178949 A3	23 Apr 1996	EP				
	AO	0258062 A2	2 Mar 1988	EP				
JT	AP	0258062 A3	2 Mar 1988	EP				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
JT	AQ	"32K x9 Bit BurstRAM Synchronous Static RAM with burst Counter and Self-Timed Write," Motorola Memory Data (MCM62486A)(No Date), pp. 7-100 to 7-109.						
JT	AR	Antola et al., "Reconfiguration of Binary Trees: The Flow-Driven Approach," 1991 International Conference on Wafer Scale Integration, 1991, pp. 141-147.						
JT	AS	Aubusson, Russell C. and Ivor Catt, "Wafer-Scale Integration—A Fault-Tolerant Procedure," IEEE Journal of Solid State Circuits, Vol. SC-13, No. 3, Jun 1978, pp. 339-344.						
Examiner /Joseph Torres/		Date Considered 10/25/2006						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								